



IEEE LEOS
LASERS & ELECTRO-OPTICS SOCIETY

Nanoscale

Imaging of Semiconductor and Biological Systems

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Boston University
 Electrical Engineering
 Physics
 Biomedical Engineering
 Photonics Center / CNN

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CENTER FOR
NANOSCIENCE AND
NANOBIOTECHNOLOGY

Outline

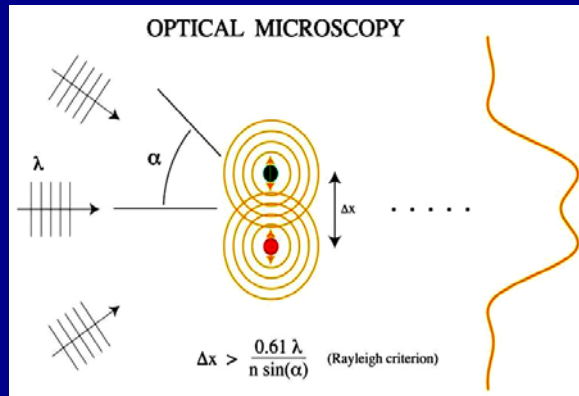
- Nano-Optics – Aperture NSOM
 - Earlier results (brief)
- Solid Immersion Lens Microscopy
 - Numerical Aperture Increasing Lens (NAIL)
 - Applications in IC imaging, thermal microscopy
 - Quantum Dot Spectroscopy
- Spectral Self-interference Microscopy
 - Preliminary results on lipid bilayers
 - DNA conformation studies



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Motivation: Resolution Limitation in Optics



$$NA = n \sin \alpha$$

$$f_{\#} = \frac{f}{2w_{01}}$$

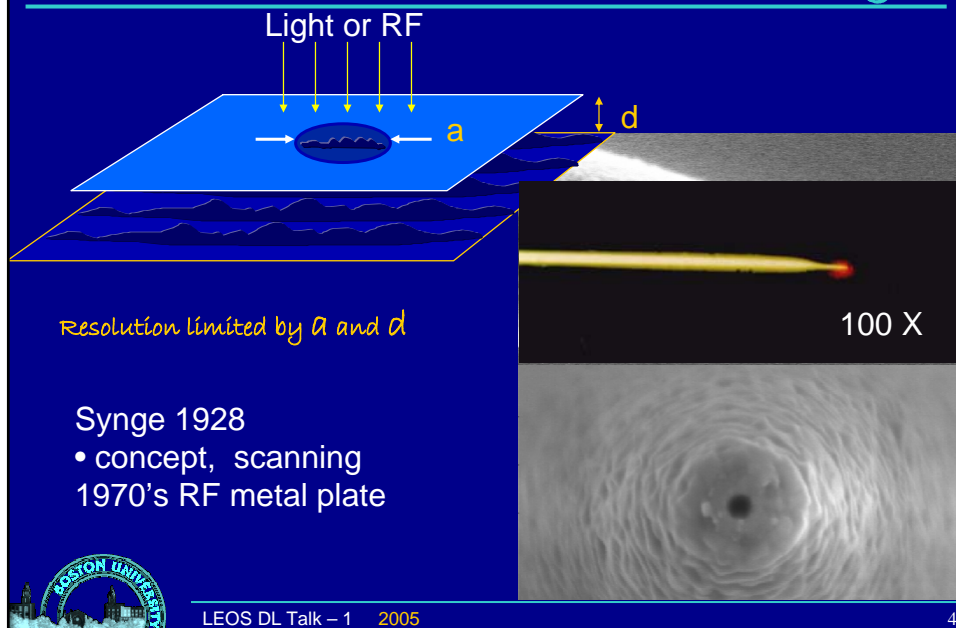
$$spotsize \approx \frac{2\lambda}{\pi NA} = \frac{\lambda}{n} \frac{4}{\pi} f_{\#}$$



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Aperture Near-Field Microscopy

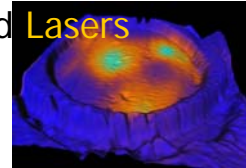
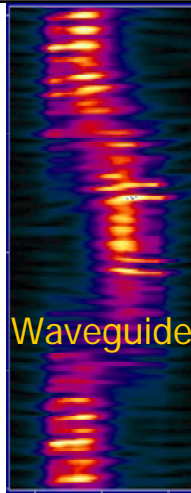
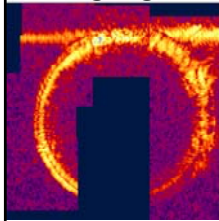


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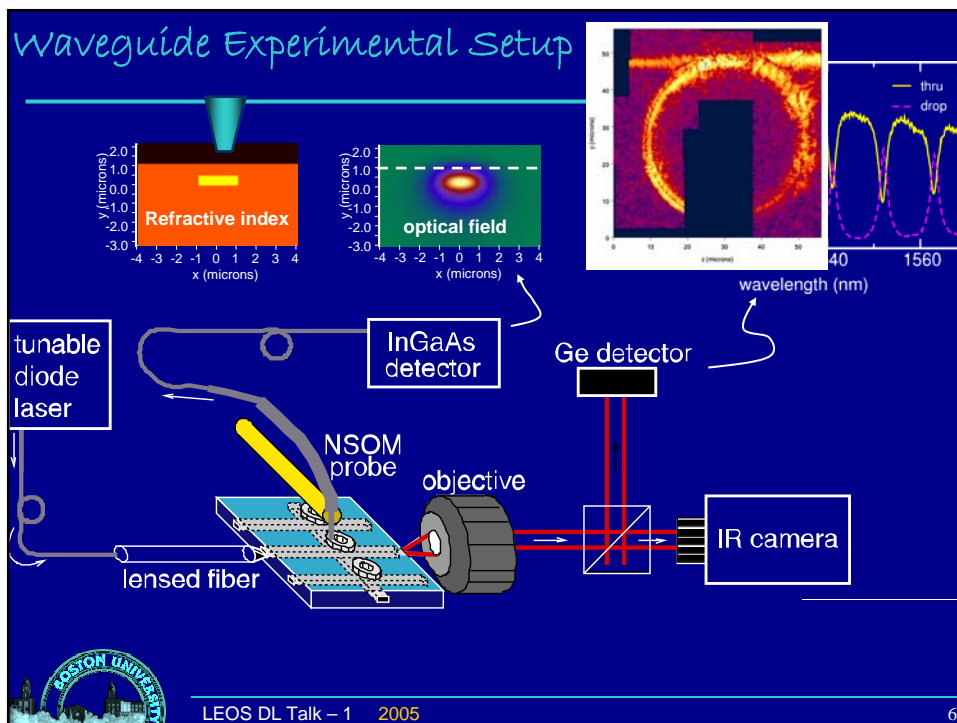
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Aperture NSOM

Imaging of PBG, Waveguide Devices and Lasers



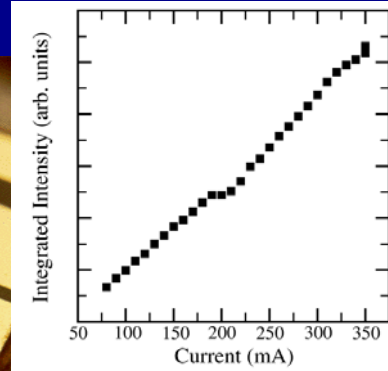
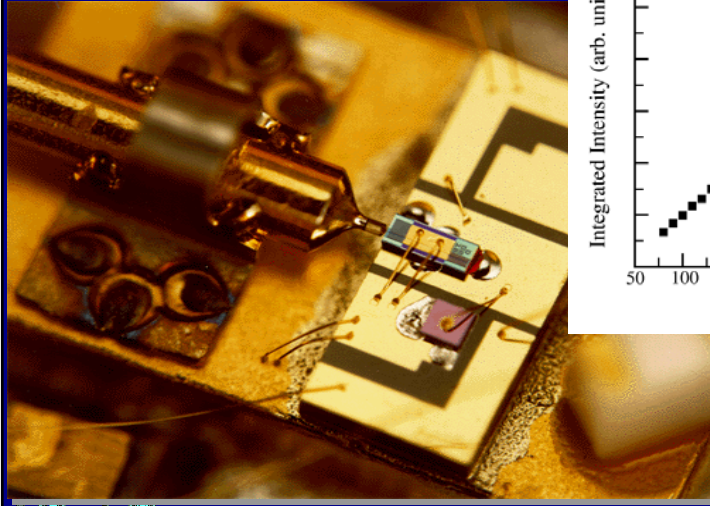
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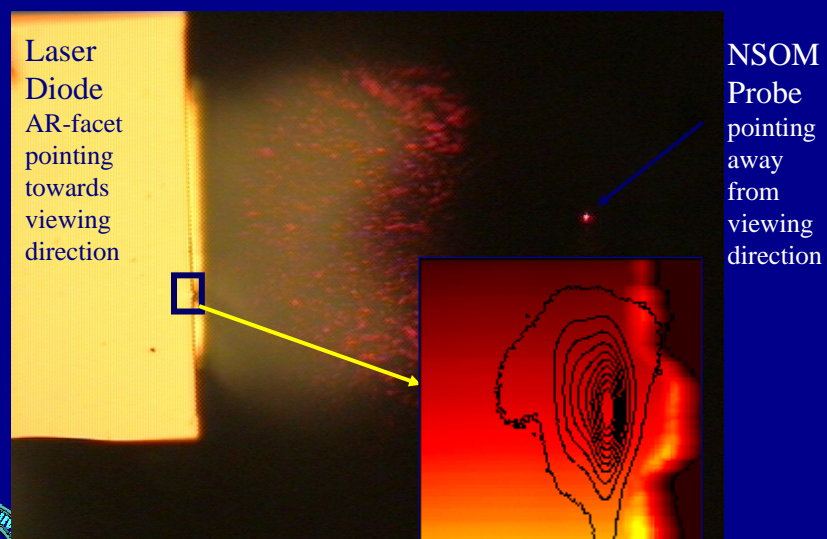
Optical fiber with wedged lens and AR coating 980 nm GRIN SCH LD



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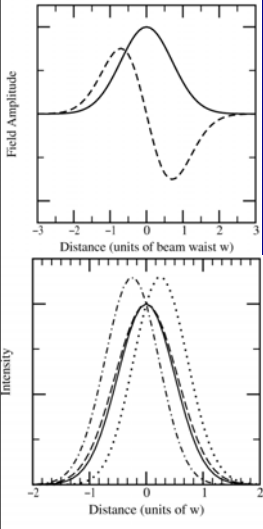
Laser Diode Facet under 40X microscope



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Lateral Beam Shifts in the Near-Field and Pointing in the Far-Field due to Mode Beating



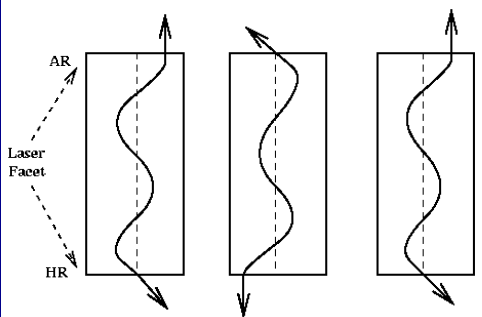
Field Amplitude


Distance (units of beam waist w)

Intensity

Distance (units of w)

$$U_{l,m}(x,y,z) = A_{l,m} \left[\frac{w_0}{w(z)} \right] G_l \left[\frac{\sqrt{2}x}{w(z)} \right] G_m \left[\frac{\sqrt{2}y}{w(z)} \right] \times \exp \left[-jkz - jk \frac{x^2 + y^2}{2R(z)} + j(l+m+1) \times \tan^{-1} \left(\frac{z}{z_0} \right) \right]$$






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PTL Dec 2000

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Outline

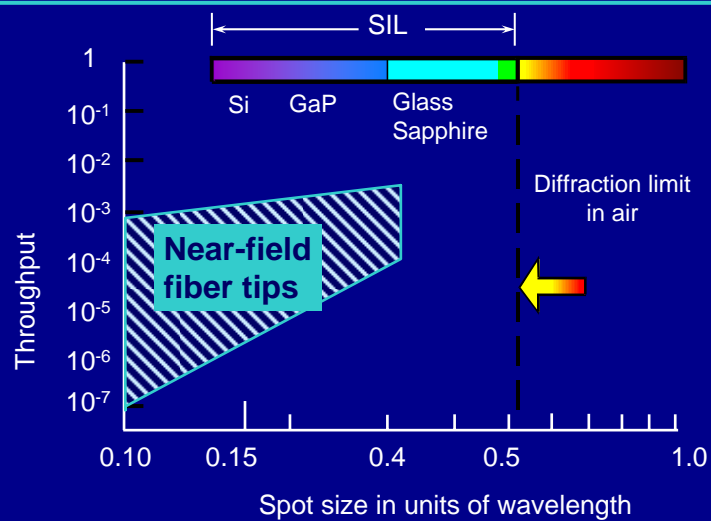
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Throughput vs. spot size



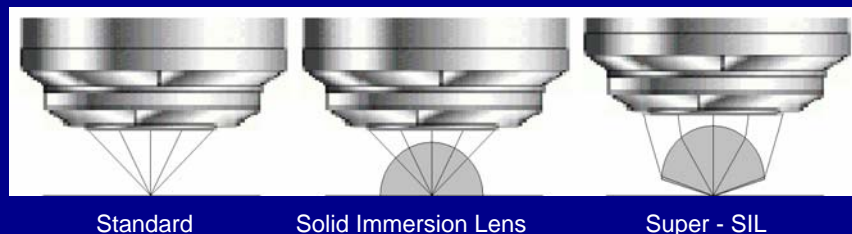
SIL with GaP

Q Wu, G.D. Feke, R.D. Grober and L.P. Ghislain, Appl. Phys. Lett. 75, 4064 (1999)

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Solid Immersion Lens Techniques Surface microscopy

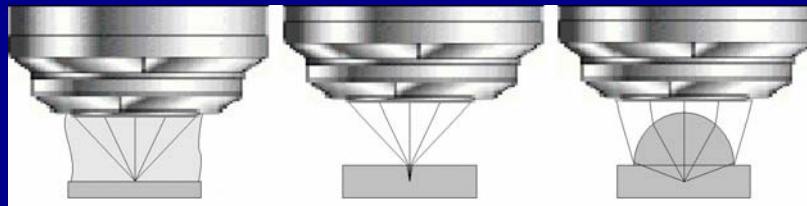


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Subsurface microscopy

Object is already "immersed"



Standard
oil Immersion

Standard
subsurface

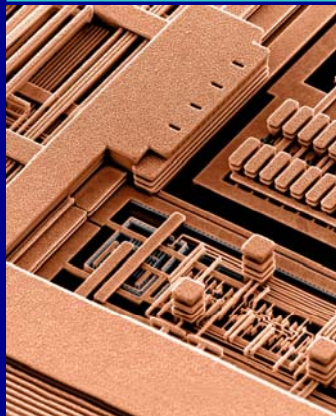
Numerical Aperture
Increasing Lens (NAIL)



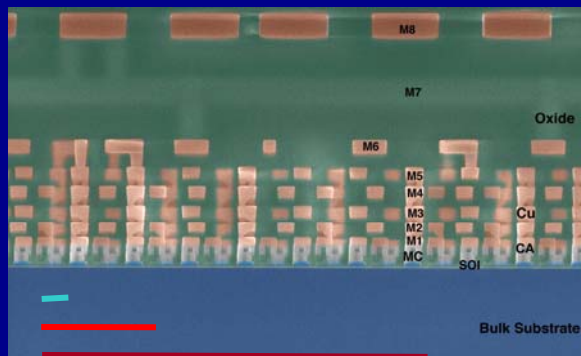
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Need for Backside Imaging for ICs



Opaque metal above buried devices often make imaging through the substrate preferable



20.0kV 20.7mm x4.00k SE(U) 4/3/03 15:06

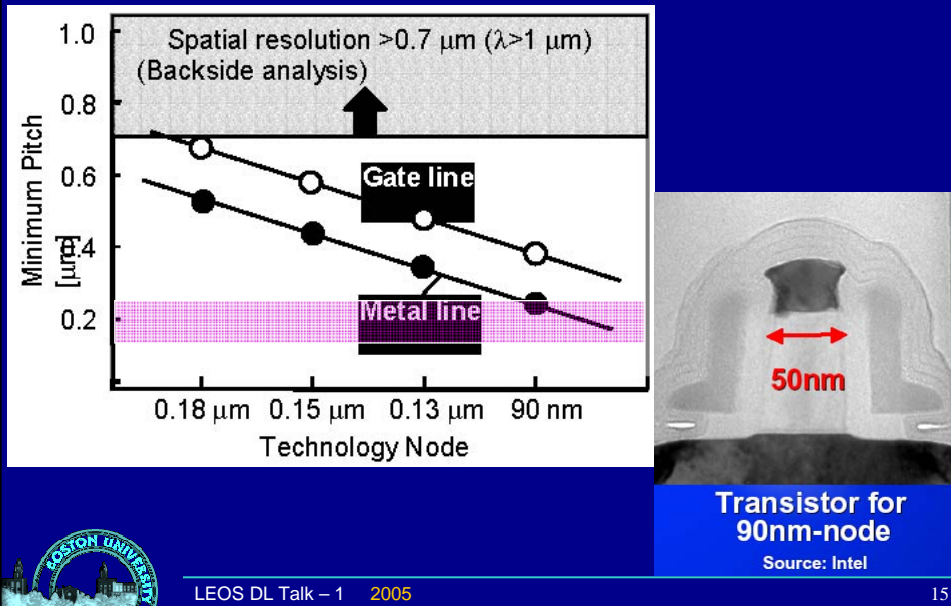
Stephen Ippolito,
PhD May 2004



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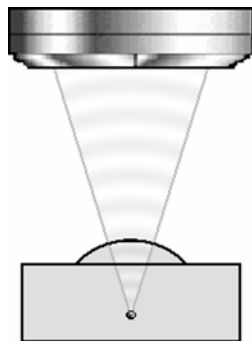
Si IC failure analysis - resolution (?)



Two types of stigmatic NAILs

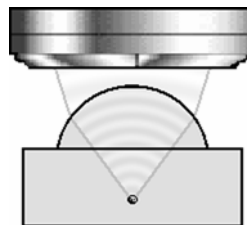
central NAIL

$$D = R - X$$



aplanatic NAIL

$$D = R(1 + 1/n) - X$$



Comparison of limitations



conventional

Light-gathering power

$$\theta_a = \sin^{-1}(1/n)$$

$$NA = 1$$

Lateral spatial resolution

$$\lambda_0/2$$

Longitudinal spatial resolution

$$n\lambda_0(1+\cos\theta_a)$$



NAIL

Light-gathering power

$$\theta_a = \pi/2$$

$$NA = n$$

Lateral spatial resolution

$$\lambda_0/2n$$

Longitudinal spatial resolution

$$\lambda_0/n$$



Qualitative Comparison

100X objective
Conventional
State-of-the-art

10X with NAIL
Boston University

Hamamatsu μ AMOS-200, IC
Failure Analysis System
1.3 μ m laser confocal scanning
optical microscope
5X, 10X, 20X, and 100X
objectives

Images are courtesy of
Hamamatsu Photonics

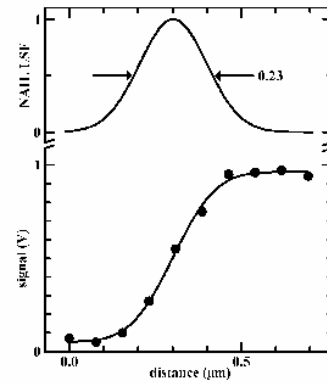
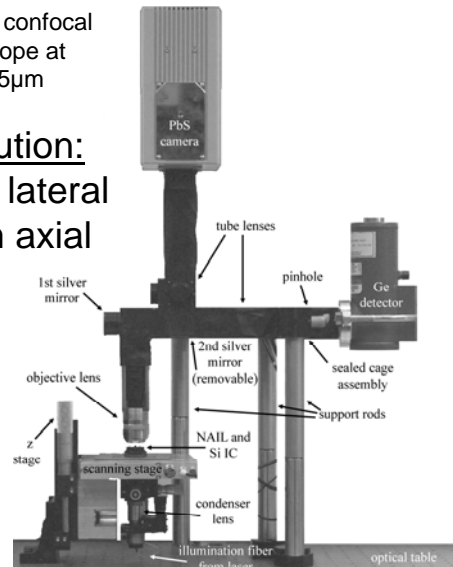
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High resolution NIR inspection microscope

Optimized confocal microscope at $\lambda=1.05\mu\text{m}$

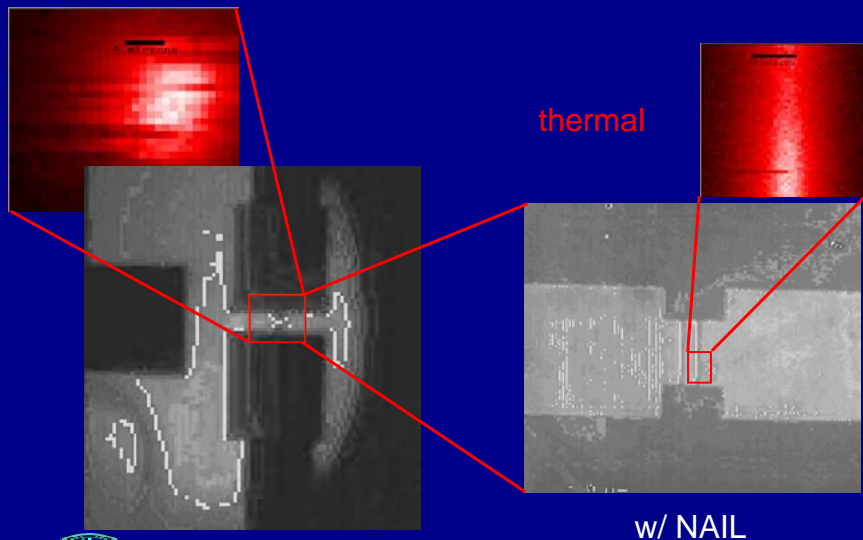
Resolution:
230 nm lateral
1.3 μm axial



APL 2001



Thermal Imaging on Al Wires



w/o NAIL

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Application: Failure Analysis

Dave Vallett and Ted Levin (IBM Microelectronics Division - Burlington, VT)

Reflectivity image
@ 1340nm

Overlay of LIVA and
reflectivity using NAIL

Reflectivity image with
NAIL @ 1340nm

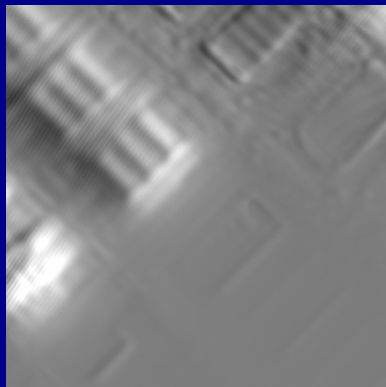
LIVA image
with NAIL @ 1064nm



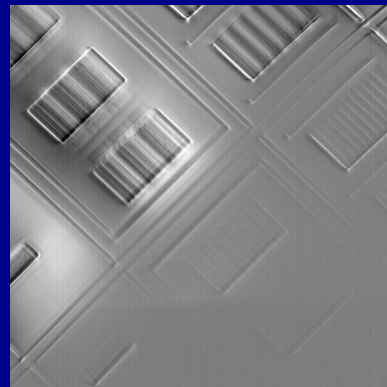
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LIVA images at 1064nm



50X + AR




20X + NAIL

10 μ m



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Hamamatsu New Generation IR-Confocal Emission Microscope PHEMOS-2000

- High mechanical accuracy
- High thermal stability
- Double-side semiautomatic probe for 300 mm wafer
- NAIL optics
- Full integrated system with photo emission and OBIRCH analysis
- Lock-in OBIRCH amplifier, MCT camera (optional)

Hamamatsu's new generation PHEMOS-2000 IR-Confocal emission microscope employs highly stabilized mechanics and optics with high thermal stability, which are requirements for effective failure analysis of current 300 mm wafer devices.


NAIL* optics are provided as standard to improve spatial resolution and light collection efficiency by significantly increasing numerical aperture.

* NAIL, Numerical Aperture Increasing Lens

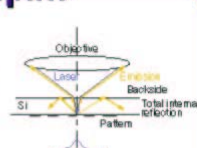
Commercial Product

Patent US 6,687,058 – Feb. 3,04


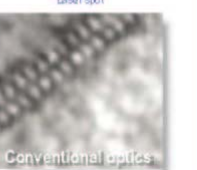
NAIL optics




High Adhesion
High NA
High resolution



Conventional optics

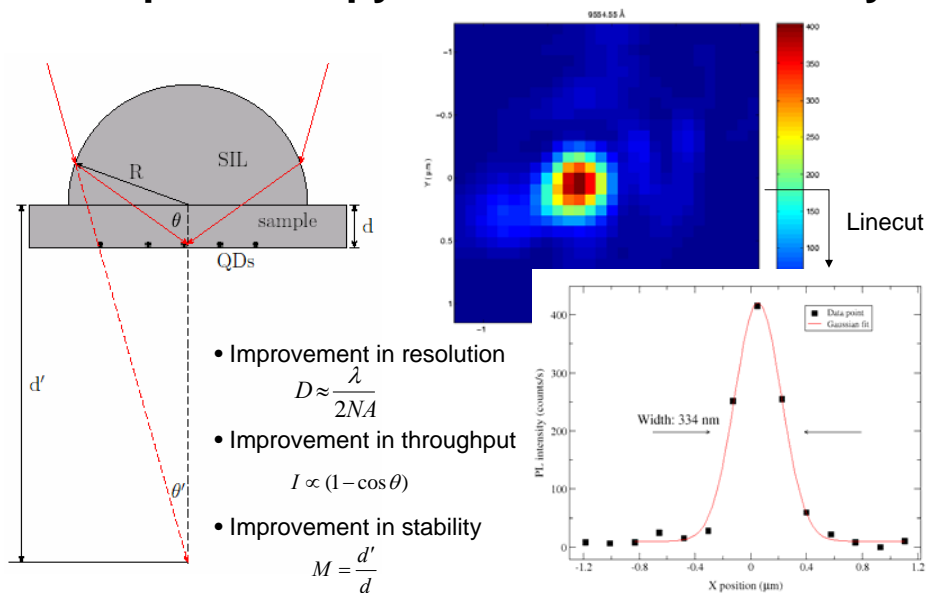
FPGA 0.18 μm rule, Field of view: 14 μm × 14 μm



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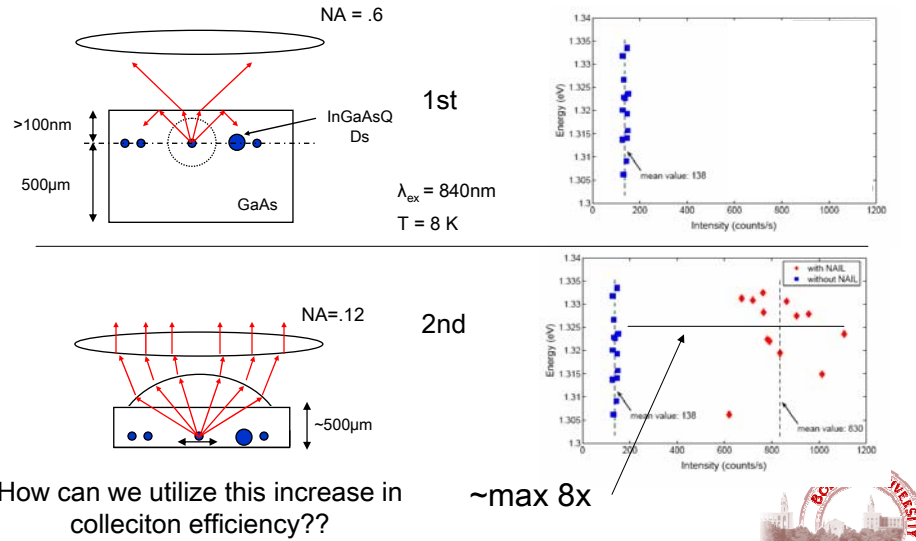
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QD Spectroscopy Resolution and stability



Use of Aplanatic NAIL

Quantify Collection Efficiency Increase



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Mehmet Dogan,
Physics, PhD 2006



Lev Moiseev,
Bio, PhD May 2003



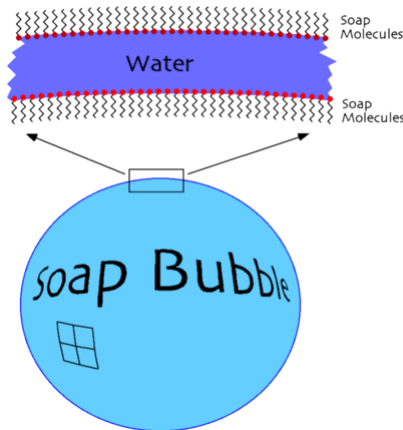
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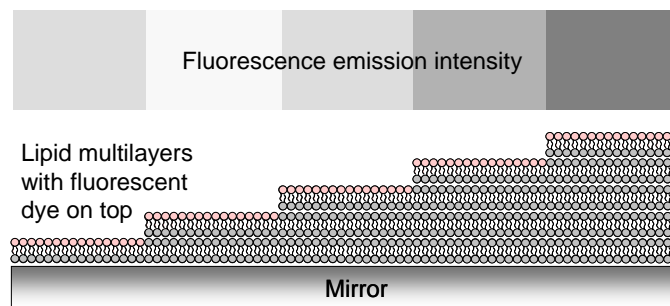
Interference of Fluorescent Emission

- 1898 O. Wiener discovers standing waves on top of silver mirror covered with photosensitive material
- 1960's K. Drexhage studies fluorescence lifetime of dyes on lipid multilayers.
- 1996 P. Fromherz shows fluorescence interferometry can determine the height of buried emitters above mirror



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Interference of Fluorescent Emission



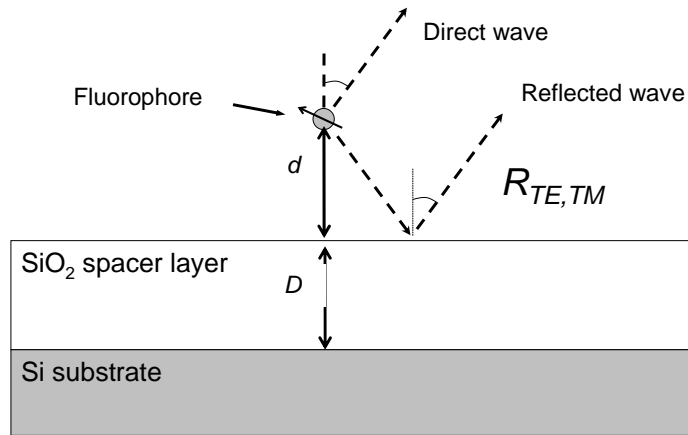
Monomolecular layers of fluorescent dyes on top of a stair-like lipid multilayers show dependence of fluorescent emission on the thickness of the lipid film

Drexhage *et al*, *Prog. Optics*, XII, p. 163, 1974



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Basic Reflectivity Model

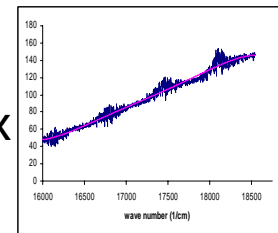
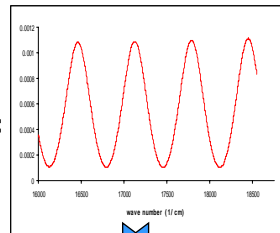
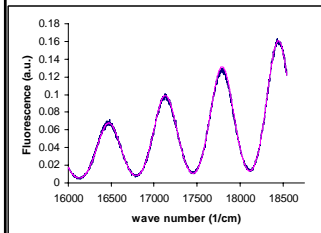


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From Spectrum to Axial Position

$$\left\{ \begin{array}{c} \text{Measured} \\ \text{Spectrum} \end{array} \right\} = \left\{ \begin{array}{c} \text{Oscillatory} \\ \text{Component} \end{array} \right\} \times \left\{ \begin{array}{c} \text{Spectral} \\ \text{Envelope} \end{array} \right\}$$



— data
— model

Axial Position with
sub-nm accuracy

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Conformation of DNA immobilized on the surface

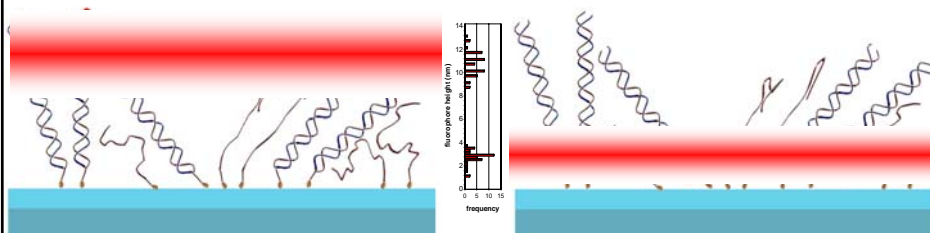
- Large DNA microarray industry dependent on hybridization of complementary sequences for detection and monitoring of gene expression
- Efficiency of hybridization depends on conformation of DNA molecules
- No known techniques (AFM, SPR, etc) that can measure extension of DNA above surface
- Utilize spectral self-interference to get a more in-depth picture of the structure and conformation of DNA molecules in an array

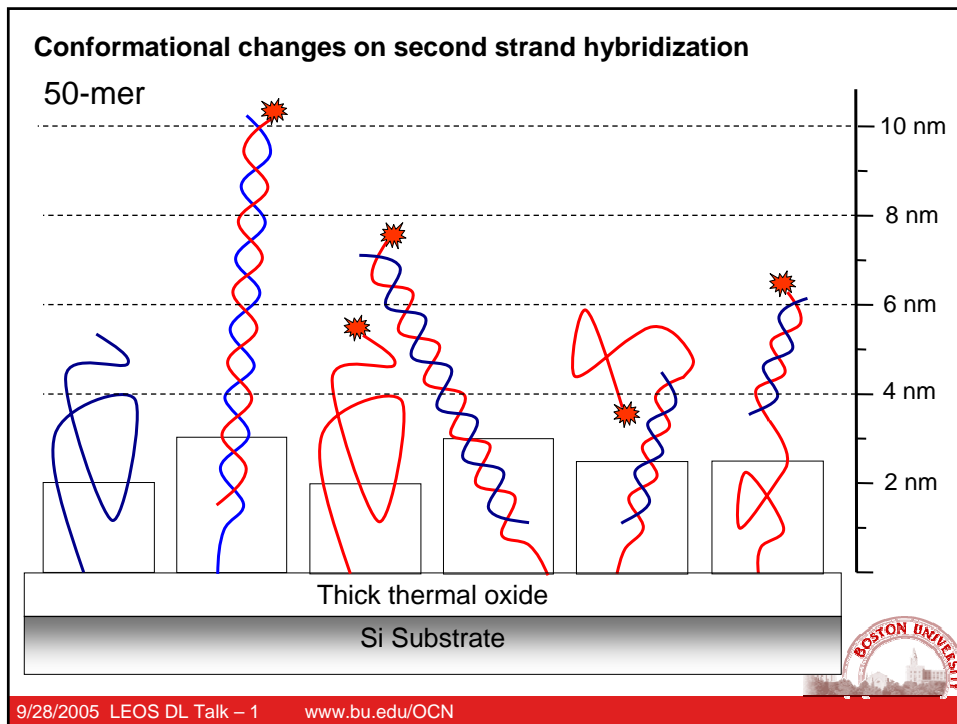


DNA on surfaces

Distal and proximal labeled second strand hybridization

- Optical density (nd) increases with hybridization
- 3' labeled second strand 2-3 nm from surface
- 5' labeled second strand 10-12 nm from surface





Conclusions on Spectral Interference

- Spectral self-interference is a novel technique for measuring the height of fluorescent molecules above a reflecting surface.
- A classical model of dipole emission that takes polarization effects into account can be used to precisely describe the oscillatory spectral component of fluorophores.
- Self-interference of the emitted light was used to trace the position of the fluorescent tag above the surface with sub-nanometer precision and thus determine the physical structure of the immobilized DNA.
- It was found that surface-bound ssDNA exists either in random coils or more extended forms depending on constraints from nearby molecules. After hybridization of a second strand the DNA adopts the conformation of a molecular brush, protruding from the surface.